



ALPHA & OMEGA
SEMICONDUCTOR

AO4406A

30V N-Channel MOSFET

General Description

The AO4406A uses advanced trench technology to provide excellent $R_{DS(ON)}$ with low gate charge. This device is suitable for high side switch in SMPS and general purpose applications.

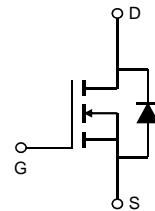
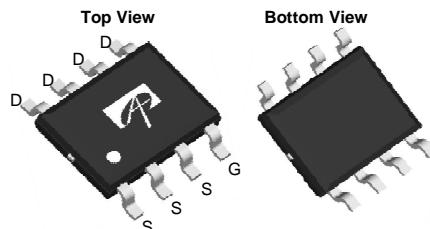
Product Summary

V_{DS}	30V
I_D (at $V_{GS}=10V$)	13A
$R_{DS(ON)}$ (at $V_{GS}=10V$)	< 11.5mΩ
$R_{DS(ON)}$ (at $V_{GS} = 4.5V$)	< 15.5mΩ

100% UIS Tested
100% R_g Tested



SOIC-8



Absolute Maximum Ratings $T_A=25^\circ C$ unless otherwise noted

Parameter	Symbol	Maximum	Units
Drain-Source Voltage	V_{DS}	30	V
Gate-Source Voltage	V_{GS}	± 20	V
Continuous Drain Current ^A	I_D	13	A
$T_A=70^\circ C$		10.4	
Pulsed Drain Current ^C	I_{DM}	100	
Avalanche Current ^C	I_{AS}	22	A
Avalanche energy $L=0.1mH$ ^C	E_{AS}	24	mJ
Power Dissipation ^B	P_D	3.1	W
$T_A=70^\circ C$		2	
Junction and Storage Temperature Range	T_J, T_{STG}	-55 to 150	°C

Thermal Characteristics

Parameter	Symbol	Typ	Max	Units
Maximum Junction-to-Ambient ^A $t \leq 10s$	$R_{\theta JA}$	31	40	°C/W
Maximum Junction-to-Ambient ^{A,D} Steady-State		59	75	°C/W
Maximum Junction-to-Lead	$R_{\theta JL}$	16	24	°C/W

Electrical Characteristics ($T_J=25^\circ\text{C}$ unless otherwise noted)

Symbol	Parameter	Conditions	Min	Typ	Max	Units
STATIC PARAMETERS						
BV_{DSS}	Drain-Source Breakdown Voltage	$I_D=250\mu\text{A}, V_{GS}=0\text{V}$	30			V
I_{DSS}	Zero Gate Voltage Drain Current	$V_{DS}=30\text{V}, V_{GS}=0\text{V}$ $T_J=55^\circ\text{C}$			1 5	μA
I_{GSS}	Gate-Body leakage current	$V_{DS}=0\text{V}, V_{GS}=\pm20\text{V}$			±100	nA
$V_{\text{GS(th)}}$	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_D=250\mu\text{A}$	1.5	1.9	2.5	V
$I_{\text{D(ON)}}$	On state drain current	$V_{GS}=10\text{V}, V_{DS}=5\text{V}$	100			A
$R_{\text{DS(ON)}}$	Static Drain-Source On-Resistance	$V_{GS}=10\text{V}, I_D=12\text{A}$ $T_J=125^\circ\text{C}$		9.5 14	11.5 17	$\text{m}\Omega$
		$V_{GS}=4.5\text{V}, I_D=10\text{A}$		12.5	15.5	$\text{m}\Omega$
g_{FS}	Forward Transconductance	$V_{DS}=5\text{V}, I_D=12\text{A}$		45		S
V_{SD}	Diode Forward Voltage	$I_S=1\text{A}, V_{GS}=0\text{V}$		0.75	1	V
I_S	Maximum Body-Diode Continuous Current				4	A
DYNAMIC PARAMETERS						
C_{iss}	Input Capacitance	$V_{GS}=0\text{V}, V_{DS}=15\text{V}, f=1\text{MHz}$	610	760	910	pF
C_{oss}	Output Capacitance		88	125	160	pF
C_{rss}	Reverse Transfer Capacitance		40	70	100	pF
R_g	Gate resistance	$V_{GS}=0\text{V}, V_{DS}=0\text{V}, f=1\text{MHz}$	0.8	1.6	2.4	Ω
SWITCHING PARAMETERS						
$Q_g(10\text{V})$	Total Gate Charge	$V_{GS}=10\text{V}, V_{DS}=15\text{V}, I_D=12\text{A}$	11	14	17	nC
$Q_g(4.5\text{V})$	Total Gate Charge		5	6.6	8	nC
Q_{gs}	Gate Source Charge		1.9	2.4	2.9	nC
Q_{gd}	Gate Drain Charge		1.8	3	4.2	nC
Q_{gs}	Gate Source Charge	$V_{GS}=4.5\text{V}, V_{DS}=15\text{V}, I_D=12\text{A}$	1.9	2.4	2.9	nC
Q_{gd}	Gate Drain Charge		1.8	3	4.2	nC
$t_{\text{D(on)}}$	Turn-On Delay Time	$V_{GS}=10\text{V}, V_{DS}=15\text{V}, R_L=1.25\Omega, R_{\text{GEN}}=3\Omega$		4.4		ns
t_r	Turn-On Rise Time			9		ns
$t_{\text{D(off)}}$	Turn-Off Delay Time			17		ns
t_f	Turn-Off Fall Time			6		ns
t_{rr}	Body Diode Reverse Recovery Time	$I_F=12\text{A}, dI/dt=500\text{A}/\mu\text{s}$	5.6	7	8	ns
Q_{rr}	Body Diode Reverse Recovery Charge	$I_F=12\text{A}, dI/dt=500\text{A}/\mu\text{s}$	6.4	8	9.6	nC

A. The value of $R_{\theta JA}$ is measured with the device mounted on 1in² FR-4 board with 2oz. Copper, in a still air environment with $T_A=25^\circ\text{C}$. The value in any given application depends on the user's specific board design.

B. The power dissipation P_D is based on $T_{J(\text{MAX})}=150^\circ\text{C}$, using $\leqslant 10\text{s}$ junction-to-ambient thermal resistance.

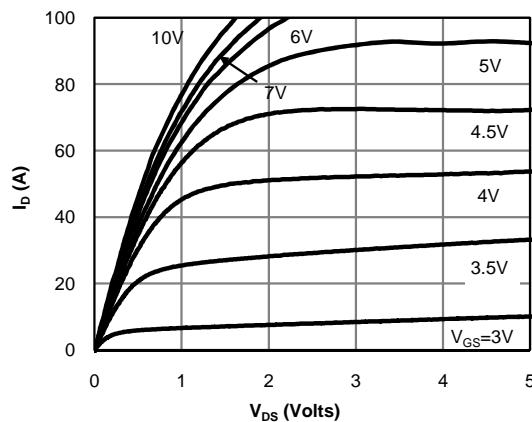
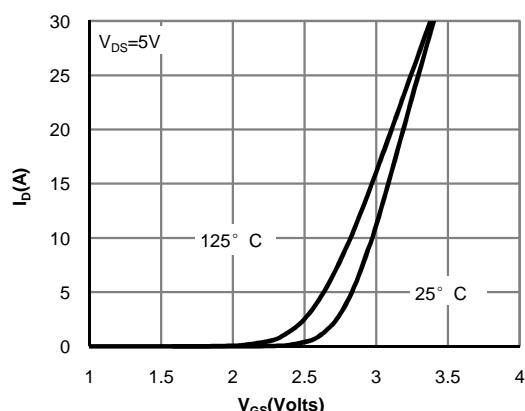
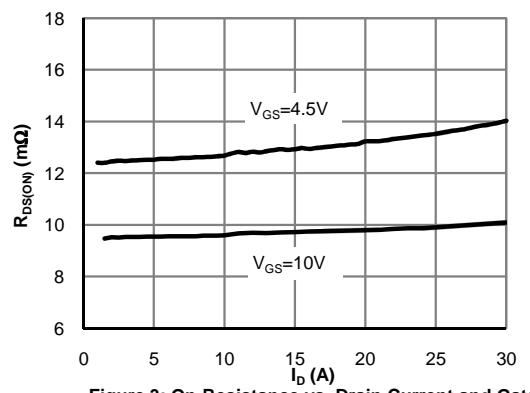
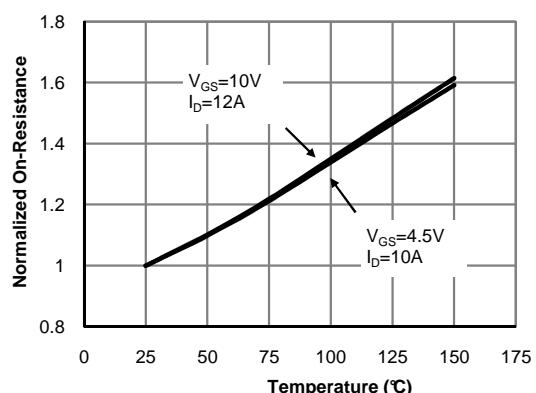
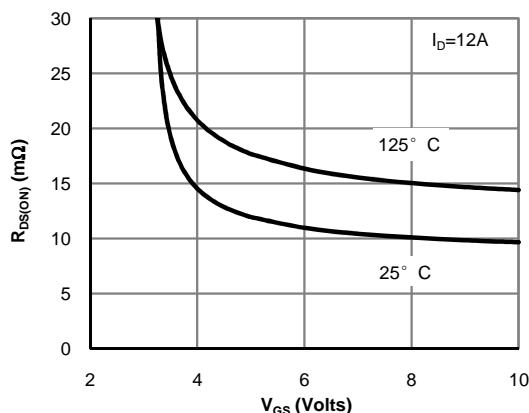
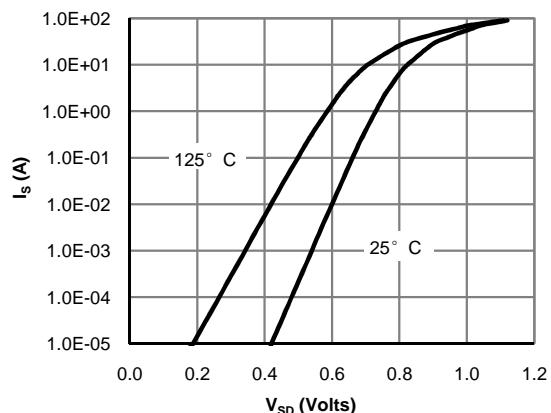
C. Repetitive rating, pulse width limited by junction temperature $T_{J(\text{MAX})}=150^\circ\text{C}$. Ratings are based on low frequency and duty cycles to keep initial $T_J=25^\circ\text{C}$.

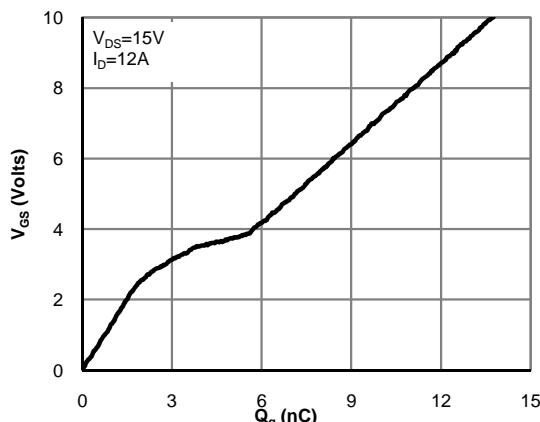
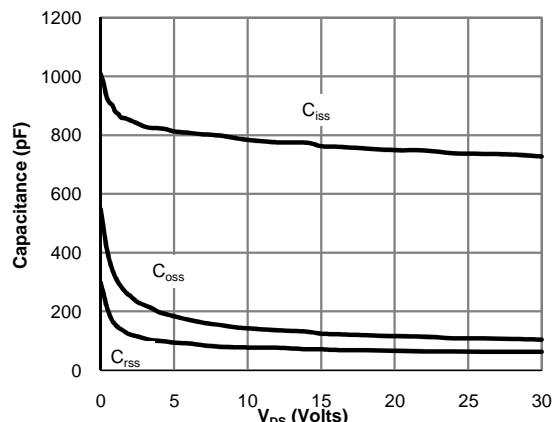
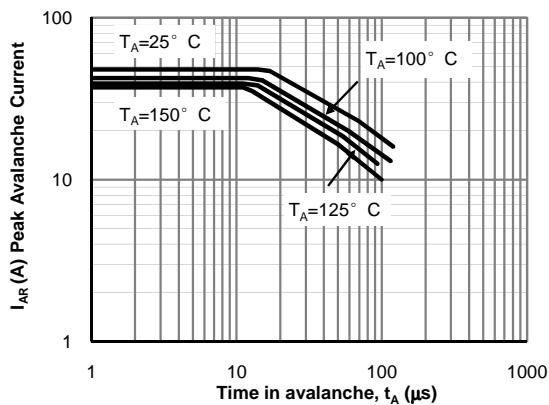
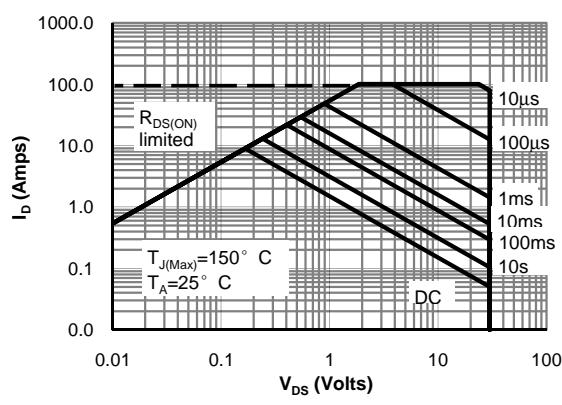
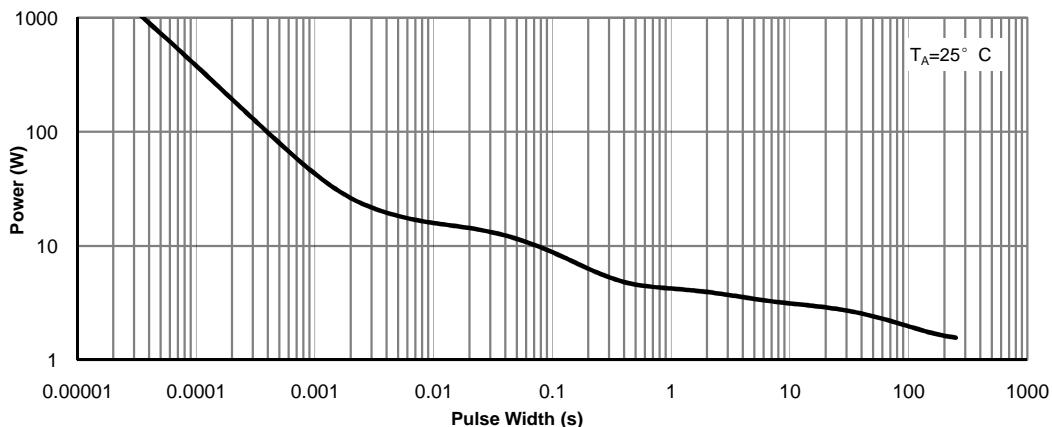
D. The $R_{\theta JA}$ is the sum of the thermal impedance from junction to lead $R_{\theta JL}$ and lead to ambient.

E. The static characteristics in Figures 1 to 6 are obtained using $<300\mu\text{s}$ pulses, duty cycle 0.5% max.

F. These curves are based on the junction-to-ambient thermal impedance which is measured with the device mounted on 1in² FR-4 board with 2oz. Copper, assuming a maximum junction temperature of $T_{J(\text{MAX})}=150^\circ\text{C}$. The SOA curve provides a single pulse rating.

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TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

Fig 1: On-Region Characteristics (Note E)

Figure 2: Transfer Characteristics (Note E)

Figure 3: On-Resistance vs. Drain Current and Gate Voltage (Note E)

Figure 4: On-Resistance vs. Junction Temperature (Note E)

Figure 5: On-Resistance vs. Gate-Source Voltage (Note E)

Figure 6: Body-Diode Characteristics (Note E)

TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

Figure 7: Gate-Charge Characteristics

Figure 8: Capacitance Characteristics

Figure 9: Single Pulse Avalanche capability (Note C)

Figure 10: Maximum Forward Biased Safe Operating Area (Note F)

Figure 11: Single Pulse Power Rating Junction-to-Ambient (Note F)

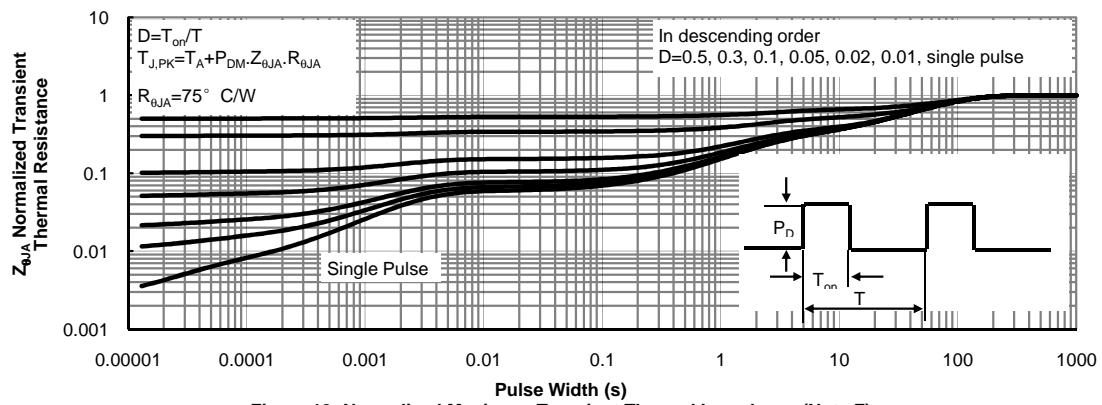
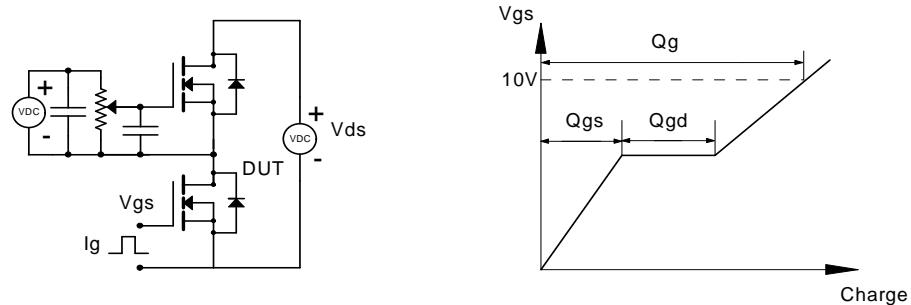
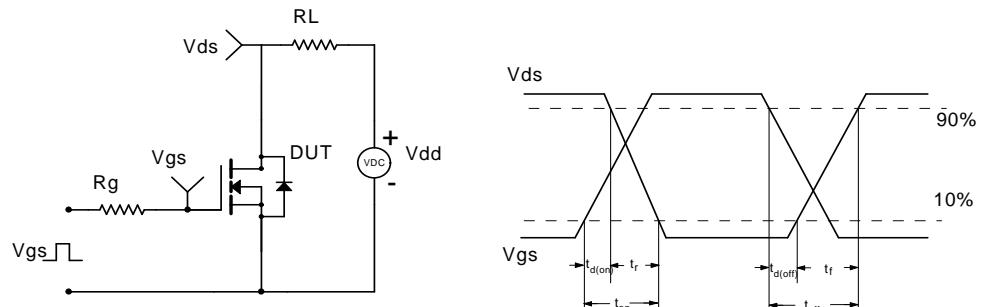
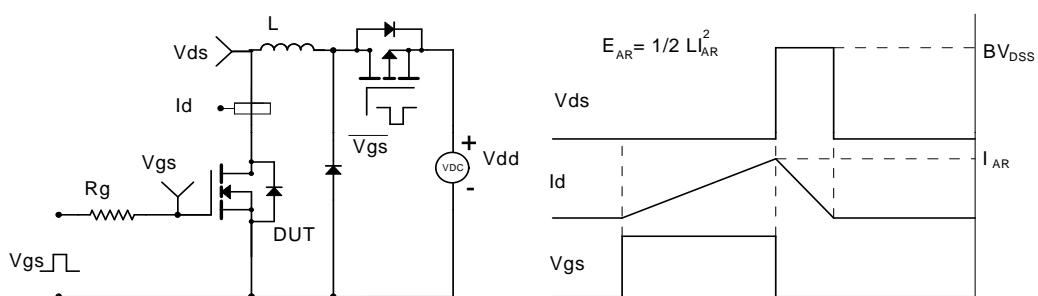
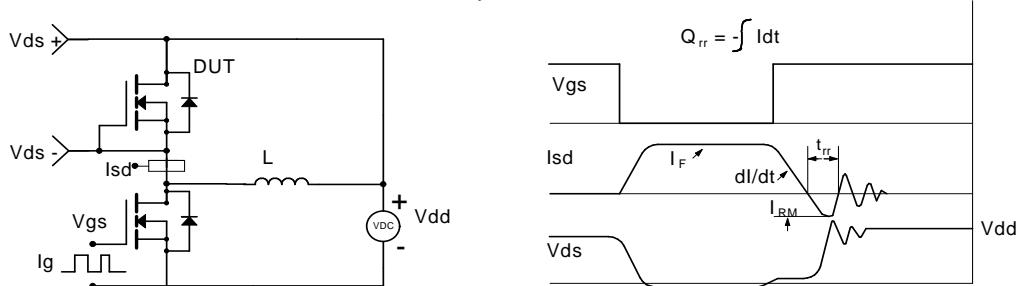
TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS


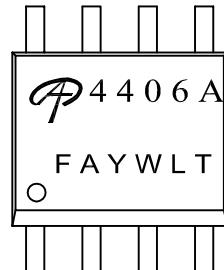
Figure 12: Normalized Maximum Transient Thermal Impedance (Note F)

Gate Charge Test Circuit & Waveform

Resistive Switching Test Circuit & Waveforms

Unclamped Inductive Switching (UIS) Test Circuit & Waveforms

Diode Recovery Test Circuit & Waveforms




Document No.	PD-00973
Version	B
Title	AO4406A Marking Description

SO-8 PACKAGE MARKING DESCRIPTION



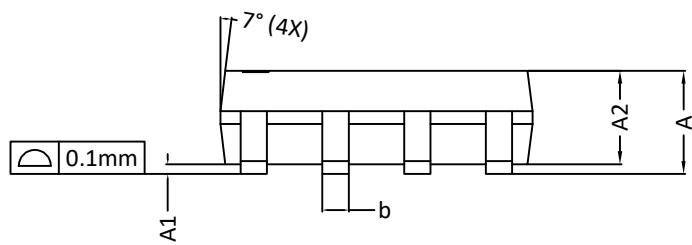
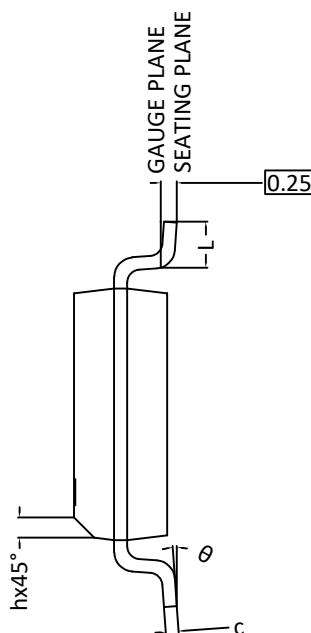
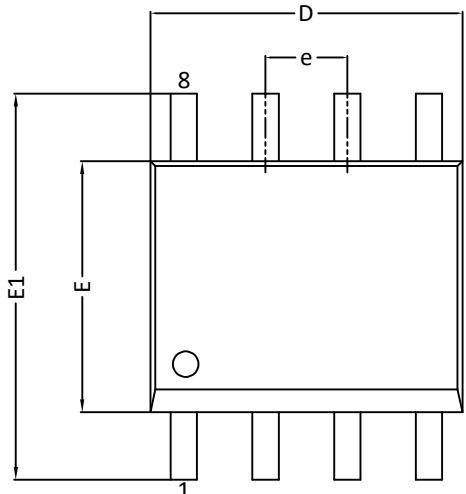
Green product

NOTE:

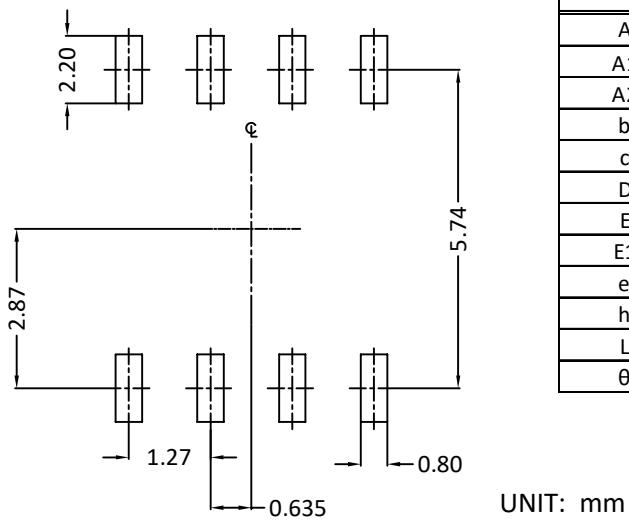
LOGO	- AOS Logo
4406A	- Part number code
F	- Fab code
A	- Assembly location code
Y	- Year code
W	- Week code
L&T	- Assembly lot code

PART NO.	DESCRIPTION	CODE
AO4406A	Green product	4406A
AO4406AL	Green product	4406A

SO8(SOP-8L) PACKAGE OUTLINE



RECOMMENDED LAND PATTERN



SYMBOLS	DIMENSION IN MM			DIMENSION IN INCHES		
	MIN	NOM	MAX	MIN	NOM	MAX
A	1.35	1.65	1.75	0.053	0.065	0.069
A1	0.10	0.15	0.25	0.004	0.006	0.010
A2	1.25	1.50	1.65	0.049	0.059	0.065
b	0.31	0.41	0.51	0.012	0.016	0.020
c	0.17	0.20	0.25	0.007	0.008	0.010
D	4.80	4.90	5.00	0.189	0.193	0.197
E	3.80	3.90	4.00	0.150	0.154	0.157
E1	5.80	6.00	6.20	0.228	0.236	0.244
e	1.27 BSC			0.050 BSC		
h	0.25	0.30	0.50	0.010	0.012	0.020
L	0.40	0.69	1.27	0.016	0.027	0.050
θ	0°	4°	8°	0°	4°	8°

NOTE

1. ALL DIMENSIONS ARE IN MILLIMETERS.
2. DIMENSIONS ARE INCLUSIVE OF PLATING.
3. PACKAGE BODY SIZES EXCLUDE MOLD FLASH AND GATE BURRS.
MOLD FLASH AT THE NON-LEAD SIDES SHOULD BE LESS THAN 6 MILS EACH.
4. DIMENSION L IS MEASURED IN GAUGE PLANE.
5. CONTROLLING DIMENSION IS MILLIMETER.
CONVERTED INCH DIMENSIONS ARE NOT NECESSARILY EXACT.



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AOS Semiconductor Product Reliability Report

AO4406A, rev C

Plastic Encapsulated Device

ALPHA & OMEGA Semiconductor, Inc

www.aosmd.com

This AOS product reliability report summarizes the qualification result for AO4406A. Accelerated environmental tests are performed on a specific sample size, and then followed by electrical test at end point. Review of final electrical test result confirms that AO4406A passes AOS quality and reliability requirements. The released product will be categorized by the process family and be routine monitored for continuously improving the product quality.

Table of Contents:

- I. Product Description
- II. Package and Die information
- III. Reliability Stress Test Summary and Results
- IV. Reliability Evaluation

I. Product Description:

The AO4406A uses advanced trench technology to provide excellent $R_{DS(ON)}$ with low gate charge. This device is suitable for high side switch in SMPS and general purpose applications.

Details refer to the datasheet.

II. Die / Package Information:

	AO4406A
Process	Standard sub-micron 30V N-Channel MOSFET
Package Type	SO-8
Lead Frame	Bare Cu
Die Attach	Ag Epoxy
Bond	Cu Wire
Mold Material	Epoxy resin with silica filler
Moisture Level	Up to Level 1

III. Reliability Stress Test Summary and Results

Test Item	Test Condition	Time Point	Total Sample Size	Number of Failures	Reference Standard
HTGB	Temp = 150°C , Vgs=100% of Vgsmax	168 / 500 / 1000 hours	924 pcs	0	JESD22-A108
HTRB	Temp = 150°C , Vds=80% of Vdsmax	168 / 500 / 1000 hours	924 pcs	0	JESD22-A108
MSL Precondition	168hr 85°C / 85%RH + 3 cycle reflow@260°C (MSL 1)	-	4620 pcs	0	JESD22-A113
HAST	130°C , 85%RH, 33.3 psi, Vds = 80% of Vdsmax	96 hours	924 pcs	0	JESD22-A110
H3TRB	85°C , 85%RH, Vds = 80% of Vdsmax	1000 hours	462 pcs	0	JESD22-A101
Autoclave	121°C , 29.7psi, RH=100%	96 hours	924 pcs	0	JESD22-A102
Temperature Cycle	-65°C to 150°C , air to air,	250 / 500 cycles	924 pcs	0	JESD22-A104
HTSL	Temp = 150°C	1000 hrs	924 pcs	0	JESD22-A103
Power Cycling	Δ Tj = 100°C	15000 cycles	462 pcs	0	AEC Q101

Note: The reliability data presents total of available generic data up to the published date.

IV. Reliability Evaluation

FIT rate (per billion): 3.27

MTTF = 34926 years

The presentation of FIT rate for the individual product reliability is restricted by the actual burn-in sample size. Failure Rate Determination is based on JEDEC Standard JESD 85. FIT means one failure per billion hours.

$$\text{Failure Rate} = \text{Chi}^2 \times 10^9 / [2 (N) (H) (Af)] = 3.27$$

$$\text{MTTF} = 10^9 / \text{FIT} = 34926 \text{ years}$$

Chi² = Chi Squared Distribution, determined by the number of failures and confidence interval

N = Total Number of units from burn-in tests

H = Duration of burn-in testing

Af = Acceleration Factor from Test to Use Conditions (Ea = 0.7eV and Tuse = 55°C)

Acceleration Factor [Af] = Exp [Ea / k (1/T_j u - 1/T_j s)]

Acceleration Factor ratio list:

	55 deg C	70 deg C	85 deg C	100 deg C	115 deg C	130 deg C	150 deg C
Af	259	87	32	13	5.64	2.59	1

T_j s = Stressed junction temperature in degree (Kelvin), K = C+273.16

T_j u =The use junction temperature in degree (Kelvin), K = C+273.16

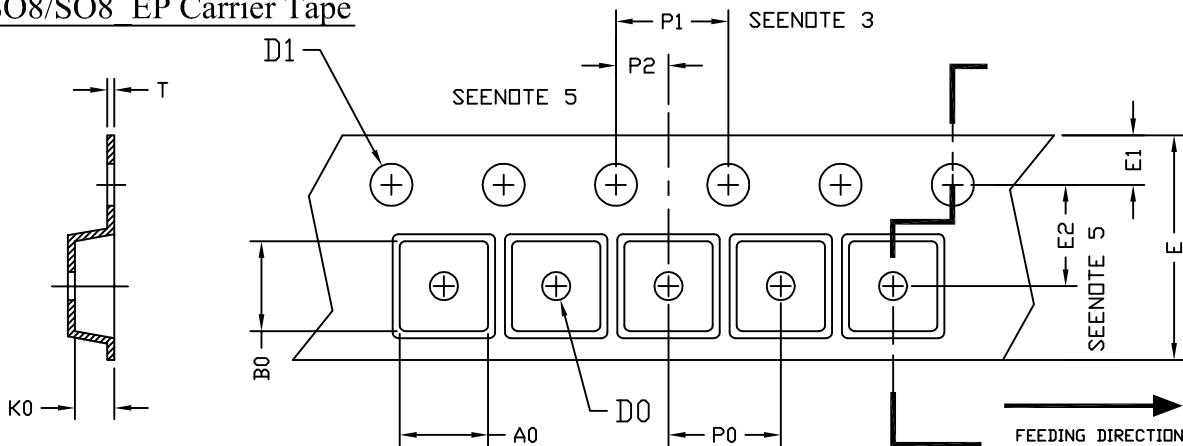
k = Boltzmann's constant, 8.617164 X 10⁻⁵eV / K



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SO7/SO8/SO8_—EP Tape and Reel Data

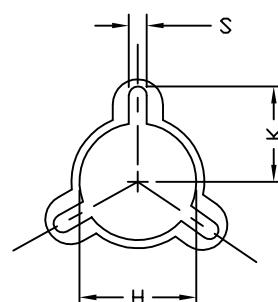
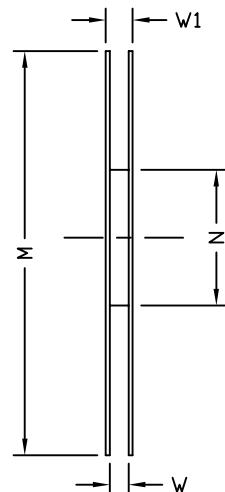
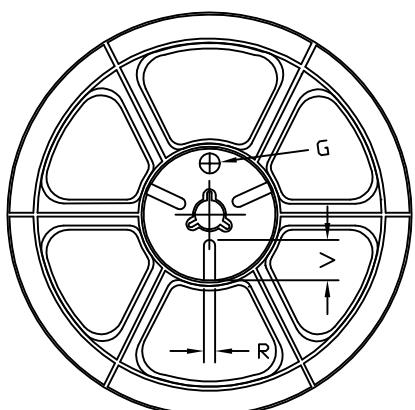
SO7/SO8/SO8 EP Carrier Tape



UNIT: MM

PACKAGE	A0	B0	K0	D0	D1	E	E1	E2	P0	P1	P2	T
SO7/SO8-8 (12 mm)	6.40 ± 0.10	5.20 ± 0.10	2.10 ± 0.10	1.60 ± 0.10	1.50 $+0.10$	12.00 ± 0.30	1.75 ± 0.10	5.50 ± 0.05	8.00 ± 0.10	4.00 ± 0.10	2.00 ± 0.05	0.25 ± 0.05

SO7/SO8/SO8 EP Reel

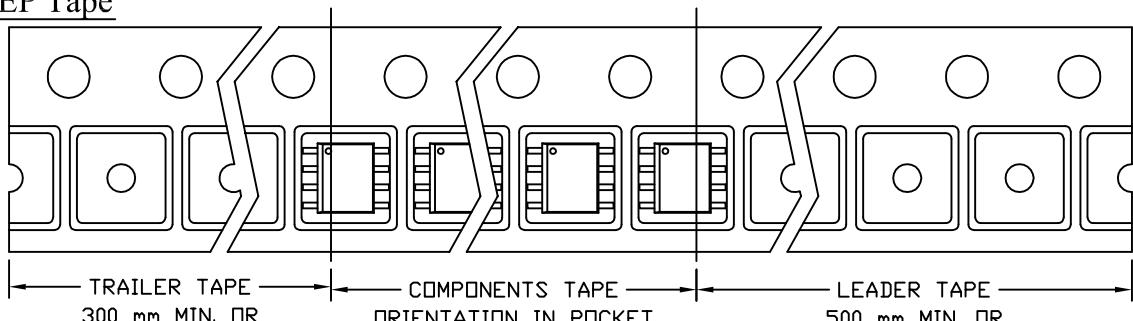


UNIT: MM

TAPE SIZE	REEL SIZE	M	N	W	W1	H	K	S	G	R	V
12 mm	Ø330	Ø330.00 ± 0.50	Ø97.00 ± 0.10	13.00 ± 0.30	13.00 ± 1.00	17.40 ± 1.00	Ø13.00 $+0.50$ -0.20	10.60	2.00 ± 0.50	---	---

SO7/SO8/SO8 EP Tape

Leader / Trailer
& Orientation



Unit Per Reel:
3000pcs